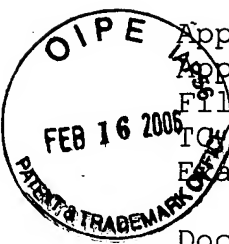


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

*Ifu*



Appl. No. : 10/727,566  
 Applicant : STÄHLER et al.  
 Filed : December 5, 2003  
 Int. A.U. : 1645  
 Examiner : To Be Assigned

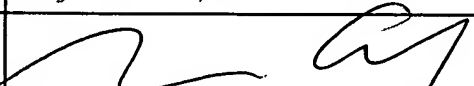
Docket No. : 2923-593  
 Customer No. : 06449  
 Confirmation No. : 7975

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

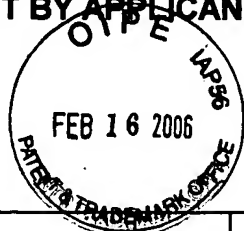
Director of the United States Patent  
 and Trademark Office  
 P.O. Box 1450  
 Alexandria, Virginia 22313-1450

Dear Sir:

Under the provisions of 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant submits herewith information that the Office may wish to consider in examination of the subject application. Applicants do not admit that the references submitted herein are prior art to the application. Materials submitted for consideration are listed on the attached Form PTO-1449. German language documents are cited because they were cited in related cases or similar cases having the same assignee in the United States or in Germany. English-language equivalents or abstracts are also submitted where available. Because no substantive action on the merits has been issued in this application, Applicants believe that no fee is due for this submission. If the Office deems that a fee is due, however, Applicants authorize the Director to charge deposit account no. 02-2135.

<b>RESPECTFULLY SUBMITTED,</b>					
NAME AND REG. NUMBER		Martha Cassidy Reg. No. 44,066			
SIGNATURE				DATE	February 16, 2006
Address		Rothwell, Figg, Ernst & Manbeck 1425 K Street, N.W., Suite 800			
City	Washington	State	D.C.	Zip Code	20005
Country	U.S.A.	Telephone	202-783-6040	Fax	202-783-6031

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**



*Complete if Known*

Application Number	10/727,566
Filing Date	December 5, 2003
First Named Inventor	STÄHLER et al.
Group Art Unit	1645
Examiner Name	To Be Assigned
Confirmation No.	7975
Attorney Docket Number	2923-593

Sheet

1

of

7

**U.S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		
		5,143,854		PIRRUNG et al.	09-01-1992
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		5,968,745		THORP et al.	10-19-1999

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		Number	Kind Code <sup>2</sup> (if known)		
		6,001,311		BRENNAN	12-14-1999
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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		WO	91/18276	A1	Kelly et al.	11-28-1991	
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		WO	99/09042		Cepheid	02-25-1999	
		WO	99/19510	A1	President and Fellows of Harvard College	04-22-1999	
Examiner Signature						Date Considered	

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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		WO	99/27140	A1	Lockheed Martin Energy Res. Corp.	06-03-1999	
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		DE	19731479	A1	Hewlett-Packard Co.	08-06-1998	AB
Examiner Signature					Date Considered		

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		Office <sup>3</sup> Code	Number <sup>4</sup>	Kind <sup>5</sup> (if known)			
		DE	19823876	A1	Institut fur Mikrotechnik Mainz GmbH	12-02-1999	AB
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		DE	69328693	T2	Beckman Coulter, Inc.	08-31-2000	
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		EP	0430248	A2	Mochida Pharmaceutical Co., Ltd.	06-05-1991	
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		EP	0549993	A1	Texas Instruments Inc.	07-07-1993	
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		JP	9288080 (Abstract)		Shinnitsuka Kankyo Eng KK	11-04-1997	AB
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Sheet	7	of	7	Attorney Docket Number	2923-593

NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>	
		Anonymous, Digital Optical Chemistry System, 12/20/99, from Internet.		
		Bertsch et al., "Study of the Spatial Resolution of a New 3D Microfabrication Process: The Microstereophotolithography Using a Dynamic Mask-generator Technique," J. Photochemistry Photobiology A: Chemistry 107:275-281, 1997.		
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		German Search Report of 08/9/1999, from DE 19839254.0 (with English translation).	✓	
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